



**Smart Cards;  
UICC-Terminal interface;  
Physical, electrical and logical test specification;  
Part 1: Terminal features  
(Release 11)**

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# Foreword

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The present document is part 1 of a multi-part deliverable covering the UICC-Terminal interface; Physical, electrical and logical test specification, as identified below:

**Part 1:** "Terminal features";

Part 2: "UICC features".

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# Modal verbs terminology

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# Introduction

The present document defines the interface tests for the Terminal/UICC interface.

The aim of the present document is to ensure interoperability between an UICC and a Terminal independently of the respective manufacturer, card issuer or operator.

Application specific tests for applications residing on an UICC are specified in ETSI TS 131 121 [4].

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